SN

**SN74** 

- Designed Specifically for High-Speed Memory Decoders and Data Transmission Systems
- Incorporate Two Enable Inputs to Simplify Cascading and/or Data Reception
- Package Options Include Plastic Small-Outline (D), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

### description

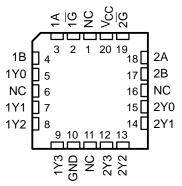
The 'HC139 are designed for high-performance memory-decoding or data-routing applications requiring very short propagation delay times. In high-performance memory systems, these decoders can minimize the effects of system decoding. When employed with high-speed memories utilizing a fast enable circuit, the delay time of these decoders and the enable time of the memory are usually less than the typical access time of the memory. This means that the effective system delay introduced by the decoders is negligible.

The 'HC139 comprise two individual 2-line to 4-line decoders in a single package. The active-low enable ( $\overline{G}$ ) input can be used as a data line in demultiplexing applications. These decoders/demultiplexers feature fully buffered inputs, each of which represents only one normalized load to its driving circuit.

	D		V PACKAGE PW PACKAGE )
1 <u></u>	1	$\cup_{16}$	] ∨ <sub>CC</sub>
1A	2	15	] V <u>c</u> c ] 2G
1B [	3	14	] 2A
1Y0 [	4	13	] 2B
1Y1 [	5	12	] 2Y0
1Y2 [	6	11	] 2Y1
1Y3 [	7	10	] 2Y2
GND [	8	9	] 2Y3
			_

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SN54HC139 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

The SN54HC139 is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to  $125^{\circ}$ C. The SN74HC139 is characterized for operation from  $-40^{\circ}$ C to  $85^{\circ}$ C.

	INPUTS		OUTPUTS							
G	SELECT			SELECT						
G	В	Α	Y0	Y1	Y2	Y3				
н	Х	Х	Н	Н	Н	Н				
L	L	L	L	н	н	н				
L	L	н	н	L	н	н				
L	Н	L	н	Н	L	Н				
L	н	Н	нннц							

FUNCTION TABLE



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

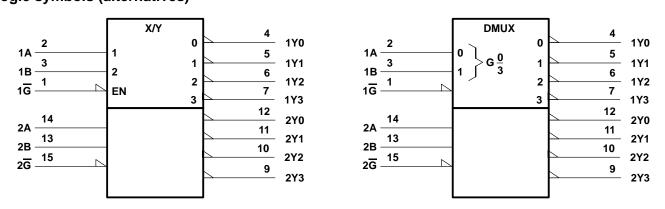
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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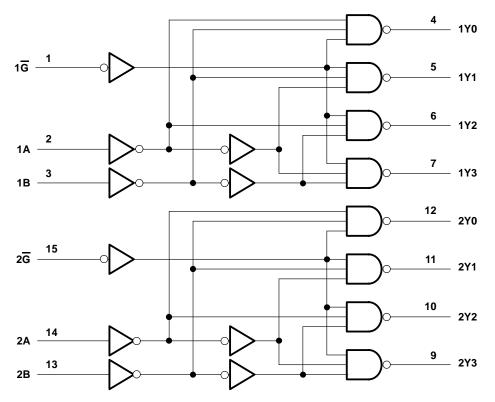
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 $^\dagger$  These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, N, PW, and W packages.

### logic diagram (positive logic)



Pin numbers shown are for the D, J, N, PW, and W packages.



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### absolute maximum ratings over operating free-air temperature range<sup>†</sup>

Supply voltage range, $V_{CC}$ Input clamp current, $I_{IK}$ ( $V_I$ < 0 or $V_I$ > $V_{CC}$ ) (so	ee Note 1)	±20 mA
Output clamp current, $I_{OK}$ (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>C</sub>	C) (see Note 1)	±20 mA
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$		±25 mA
Continuous current through V <sub>CC</sub> or GND		±50 mA
Package thermal impedance, $\theta_{JA}$ (see Note 2)	: D package	113°C/W
	N package	
	PW package	149°C/W
Storage temperature range, T <sub>stg</sub>		

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

#### recommended operating conditions

			SN	SN54HC139			SN74HC139		
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage		2	5	6	2	5	6	V
		$V_{CC} = 2 V$	1.5			1.5			
VIH	VIH High-level input voltage	V <sub>CC</sub> = 4.5 V	3.15			3.15			V
		ACC = 6 A	4.2			4.2			
VIL Low-level input		$V_{CC} = 2 V$	0		0.5	0		0.5	V
	Low-level input voltage	$V_{CC} = 4.5 V$	0		1.35	0		1.35	
		ACC = 6 A	0		1.8	0		1.8	
VI	Input voltage		0		VCC	0		VCC	V
VO	Output voltage		0		VCC	0		VCC	V
		$V_{CC} = 2 V$	0		1000	0		1000	
tt Input transition (rise and fal	Input transition (rise and fall) time	V <sub>CC</sub> = 4.5 V	0		500	0		500	ns
		VCC = 6 V	0		400	0		400	
TA	Operating free-air temperature		-55		125	-40		85	°C



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		Vaa	Т	A = 25°C	;	SN54H	C139	SN74HC139		UNIT
PARAMETER			Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	1.9	1.998		1.9		1.9		
		I <sub>OH</sub> = -20 μA	4.5 V	4.4	4.499		4.4		4.4		
∨он	V <sub>OH</sub> V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>		6 V	5.9	5.999		5.9		5.9		V
		$I_{OH} = -4 \text{ mA}$	4.5 V	3.98	4.3		3.7		3.84		
		I <sub>OH</sub> = -5.2 mA	6 V	5.48	5.8		5.2		5.34		
		I <sub>OL</sub> = 20 μA	2 V		0.002	0.1		0.1		0.1	
			4.5 V		0.001	0.1		0.1		0.1	
VOL	$V_I = V_{IH} \text{ or } V_{IL}$		6 V		0.001	0.1		0.1		0.1	V
		I <sub>OL</sub> = 4 mA	4.5 V		0.17	0.26		0.4		0.33	
		I <sub>OL</sub> = 5.2 mA	6 V		0.15	0.26		0.4		0.33	
li	$V_{I} = V_{CC} \text{ or } 0$		6 V		±0.1	±100		±1000		±1000	nA
ICC	$V_{I} = V_{CC} \text{ or } 0,$	I <sub>O</sub> = 0	6 V			8		160		80	μΑ
Ci			2 V to 6 V		3	10		10		10	pF

switching characteristics over recommended operating free-air temperature range,  $C_L = 50 \text{ pF}$  (unless otherwise noted) (see Figure 1)

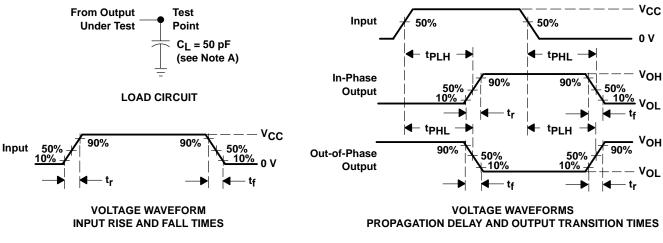
PARAMETER	FROM	TO (OUTPUT)	Vaa	Т	ן = 25°C	;	SN54H	C139	SN74H	C139	UNIT		
FARAINETER	(INPUT)		Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT		
		Y	2 V		47	175		255		220			
	A or B		4.5 V		14	35		51		44			
<sup>t</sup> pd			6 V		12	30		44		38	ns		
	<sup>t</sup> pd <u>G</u>		2 V		39	175		255		220			
		Y	Y 4.5 V		11	35		51		44			
		6 V		10	30		44		38				
tt			2 V		38	75		110		95			
			Y	Y	Y	4.5 V		8	15		22		19
			6 V		6	13		19		16			

### operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
Cpd	Power dissipation capacitance per decoder	No load	25	pF



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### PARAMETER MEASUREMENT INFORMATION

NOTES: A. CL includes probe and test-fixture capacitance.

- B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>f</sub> = 6 ns. t<sub>f</sub> = 6 ns.
- C. The outputs are measured one at a time with one input transition per measurement.
- D.  $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .

### Figure 1. Load Circuit and Voltage Waveforms



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